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February 12, 2002

To: Commissioner of Patents and Trademarks

Washington, D.C. 20231

Fr: George O. Saile, Reg. No. 19,572

20 McIntosh Drive

Poughkeepsie, N.Y. 12603

Subject:

Serial No. 10/002,986 11/30/01

Burn J. Lin, Shinn-Sheng Yu, Bang Chein Ho

IMPROVEMENT OF CONTACT HOLE PRINTING BY PACKING AND UNPACKING

Grp. Art Unit:

## INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citatio In An Application.

The following Patents and/or Publications are submitted to comply with the duty of disclosure under CFR 1.97-1.99 and 37 CFR 1.56. Copies of each document is included herewith.

## CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner of Patents and Trademarks, Washington, D.C. 20231, on February 15, 2002.

Stephen B. Ackerman, Reg.# 37761

Signature/Date

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TSMC-01-376

- U.S. Patent 5,573,634 to Ham, "Method for Forming Contact Holes of a Semiconductor Device," discloses a double exposure contact hole method.
- U.S. Patent 6,218,057 to Cirelli et al., "Lithographic Process Having Sub-Wavelength Resolution," discloses a lithographic process for contact holes using 2 masks/exposures.
- U.S. Patent 6,238,850 to Bula et al., "Method of Forming Sharp Corners in a Photoresist Layer," discloses a photo method for contact holes using 2 masks/exposures.
- U.S. Patent 5,308,741 to Kemp, "Lithographic Method Using Double Exposure Techniques, Mask Position Shifting and Light Phase Shifting," discloses a lithographic method using double exposures, physical mask shifting, and light phase shifting used to form masking features on a substrate masking layer.
- U.S. Patent 5,897,975 to Ahn et al., "Phase Shift Mask for Formation of Contact Holes Having Micro Dimension," discusses a phase shift mask having a multi-layer structure, fabricated by forming a plurality of uniformly spaced phase shift layers on a quartz substrate, capable of forming contact holes with a micro dimension smaller that the wavelength used in the light exposure procedure.

TSMC-01-376

U.S. Patent 5,795,686 to Talizawa et al., "Pattern Forming Method and Method of Manufacturing Liquied Crystal Display Device," discusses a pattern forming method of forming an overall pattern by connecting a plurality of pattern forming regions.

Sincerely,

Stephen B. Ackerman,

Reg. No. 37761